

International Rectifier

HEXFET® POWER MOSFET

Provisional Data Sheet No. PD-9.550B

JANTX2N6849
JANTXV2N6849
[REF:MIL-PRF-19500/564]
[GENERIC:IRFF9130]
P-CHANNEL

-100 Volt, 0.30Ω HEXFET

HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry achieves very low on-state resistance combined with high transconductance.

HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, and high energy pulse circuits, and virtually any application where high reliability is required.

Product Summary

Part Number	BVDSS	RDS(on)	ID
JANTX2N6849	-100V	0.30Ω	-6.5A
JANTXV2N6849			

Features:

- Avalanche Energy Rating
- Dynamic dv/dt Rating
- Simple Drive Requirements
- Ease of Paralleling
- Hermetically Sealed

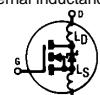
Absolute Maximum Ratings

	Parameter	JANTX2N6849, JANTXV2N6849	Units
ID @ VGS = -10V, TC = 25°C	Continuous Drain Current	-6.5	A
ID @ VGS = -10V, TC = 100°C	Continuous Drain Current	-4.1	
IMD	Pulsed Drain Current ①	-25	
PD @ TC = 25°C	Max. Power Dissipation	25	W
	Linear Derating Factor	0.20	W/K ⑤
VGS	Gate-to-Source Voltage	±20	V
dv/dt	Peak Diode Recovery dv/dt ③	-5.5	V/ns
TJ TSTG	Operating Junction Storage Temperature Range	-55 to 150	°C
	Lead Temperature	300 (0.063 in. (1.6mm) from case for 10.5 seconds)	
	Weight	0.98 (typical)	g

JANTX2N6849, JANTXV2N6849 Device

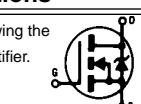
Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (Unless Otherwise Specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	-100	—	—	V	$\text{V}_{\text{GS}} = 0\text{V}$, $\text{I}_D = -1.0 \text{ mA}$
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Temperature Coefficient of Breakdown Voltage	—	-0.10	—	V°C	Reference to 25°C , $\text{I}_D = -1.0 \text{ mA}$
$\text{RDS}(\text{on})$	Static Drain-to-Source On-State Resistance	—	—	0.30	Ω	$\text{V}_{\text{GS}} = -10\text{V}$, $\text{I}_D = -4.1\text{A}$ ^④
		—	—	0.345		$\text{V}_{\text{GS}} = -10\text{V}$, $\text{I}_D = -6.5\text{A}$
$\text{VGS}(\text{th})$	Gate Threshold Voltage	-2.0	—	-4.0	V	$\text{V}_{\text{DS}} = \text{V}_{\text{GS}}$, $\text{I}_D = -250\mu\text{A}$
gfs	Forward Transconductance	2.5	—	—	$\text{S} (\text{d})$	$\text{V}_{\text{DS}} > -15\text{V}$, $\text{I}_{\text{DS}} = -4.1\text{A}$ ^④
IDSS	Zero Gate Voltage Drain Current	—	—	-25	μA	$\text{V}_{\text{DS}} = 0.8 \times \text{Max Rating}$, $\text{V}_{\text{GS}} = 0\text{V}$
		—	—	-250		$\text{V}_{\text{DS}} = 0.8 \times \text{Max Rating}$ $\text{V}_{\text{GS}} = 0\text{V}$, $T_j = 125^\circ\text{C}$
IGSS	Gate-to-Source Leakage Forward	—	—	-100	nA	$\text{V}_{\text{GS}} = -20\text{V}$
IGSS	Gate-to-Source Leakage Reverse	—	—	100		$\text{V}_{\text{GS}} = 20\text{V}$
Q_q	Total Gate Charge	14.7	—	34.8	nC	$\text{V}_{\text{GS}} = -10\text{V}$, $\text{I}_D = -6.5\text{A}$
Q_{gs}	Gate-to-Source Charge	1.0	—	7.1		$\text{V}_{\text{DS}} = \text{Max. Rating} \times 0.5$
Q_{gd}	Gate-to-Drain ("Miller") Charge	2.0	—	21	ns	see figures 6 and 13
$\text{t}_d(\text{on})$	Turn-On Delay Time	—	—	60		$\text{VDD} = -50\text{V}$, $\text{I}_D = -6.5\text{A}$,
t_r	Rise Time	—	—	140	ns	$\text{RG} = 7.5\Omega$, $\text{VGS} = -10\text{V}$
$\text{t}_d(\text{off})$	Turn-Off Delay Time	—	—	140		see figure 10
t_f	Fall Time	—	—	140		
L_D	Internal Drain Inductance	—	5.0	—	nH	Measured from the drain lead, 6mm (0.25 in.) from package to center of die.
L_S	Internal Source Inductance	—	15	—		Measured from the source lead, 6mm (0.25 in.) from package to source bonding pad.
C_{iss}	Input Capacitance	—	800	—	pF	$\text{V}_{\text{GS}} = 0\text{V}$, $\text{V}_{\text{DS}} = -25\text{V}$
C_{oss}	Output Capacitance	—	350	—		$f = 1.0 \text{ MHz}$
Crss	Reverse Transfer Capacitance	—	125	—		see figure 5



Source-Drain Diode Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I_S	Continuous Source Current (Body Diode)	—	—	-6.5	A	Modified MOSFET symbol showing the integral reverse p-n junction rectifier.
ISM	Pulse Source Current (Body Diode) ^①	—	—	-25		
V_{SD}	Diode Forward Voltage	—	—	-4.7	V	$T_j = 25^\circ\text{C}$, $\text{I}_S = -6.5\text{A}$, $\text{V}_{\text{GS}} = 0\text{V}$ ^④
t_{rr}	Reverse Recovery Time	—	—	250	ns	$T_j = 25^\circ\text{C}$, $\text{I}_F = -6.5\text{A}$, $d\text{I}/dt \leq -100\text{A}/\mu\text{s}$
QRR	Reverse Recovery Charge	—	—	3.0	μC	$\text{VDD} \leq -50\text{V}$ ^④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $\text{L}_S + \text{L}_D$.				



Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
R_{thJC}	Junction-to-Case	—	—	5.0	K/W	
	Junction-to-Ambient	—	—	175		Typical socket mount

JANTX2N6849, JANTXV2N6849 Device

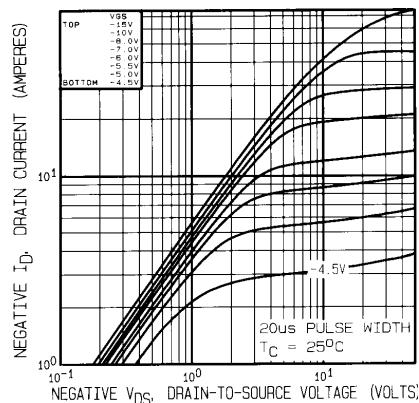


Fig. 1 — Typical Output Characteristics
 $T_c = 25^\circ\text{C}$

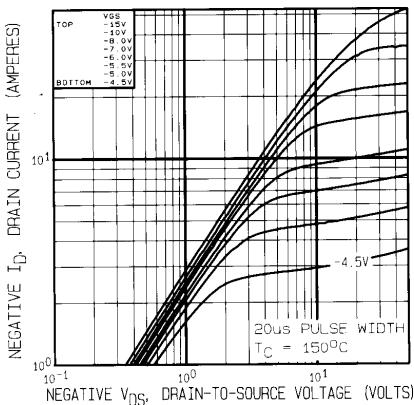


Fig. 2 — Typical Output Characteristics
 $T_c = 150^\circ\text{C}$

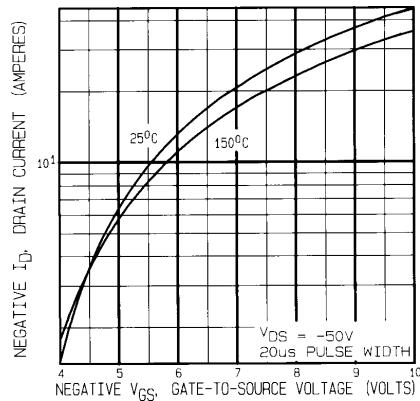


Fig. 3 — Typical Transfer Characteristics

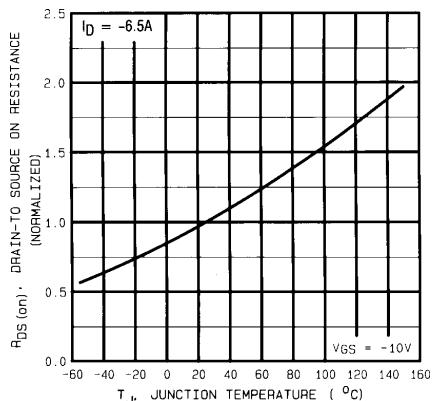


Fig. 4 — Normalized On-Resistance Vs. Temperature

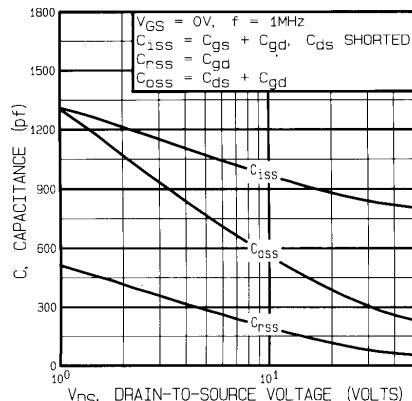


Fig. 5 — Typical Capacitance Vs. Drain-to-Source Voltage

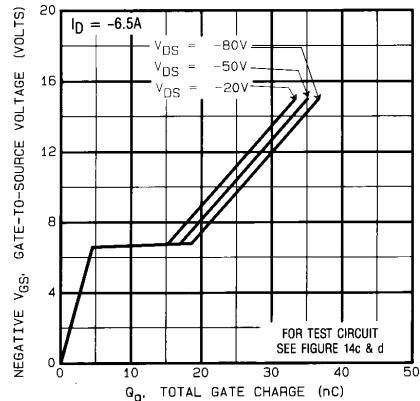


Fig. 6 — Typical Gate Charge Vs. Gate-to-Source Voltage

JANTX2N6849, JANTXV2N6849 Device

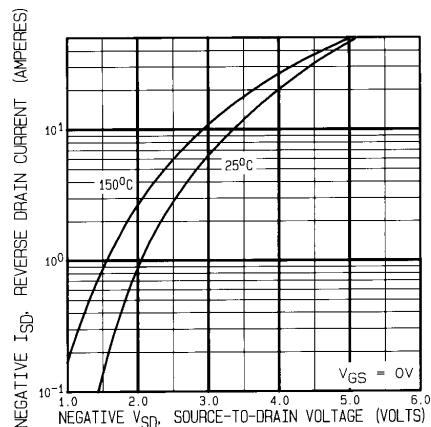


Fig. 7 — Typical Source-to-Drain Diode Forward Voltage

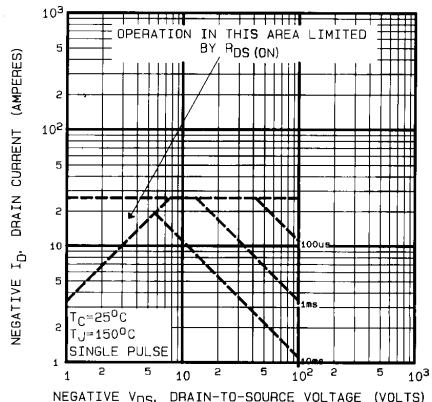


Fig. 8 — Maximum Safe Operating Area

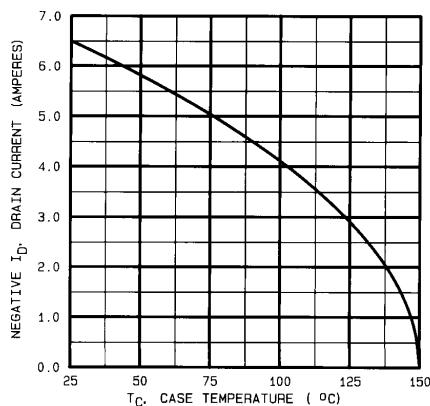


Fig. 9 — Maximum Drain Current Vs. Case Temperature

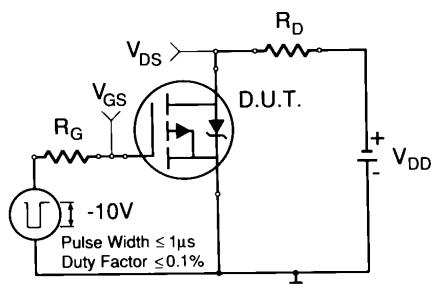


Fig. 10a — Switching Time Test Circuit

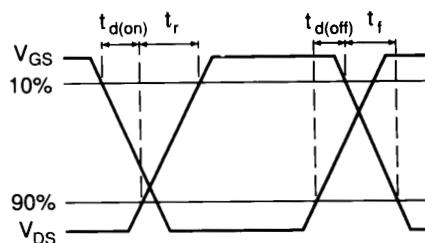


Fig. 10b — Switching Time Waveforms

JANTX2N6849, JANTXV2N6849 Device

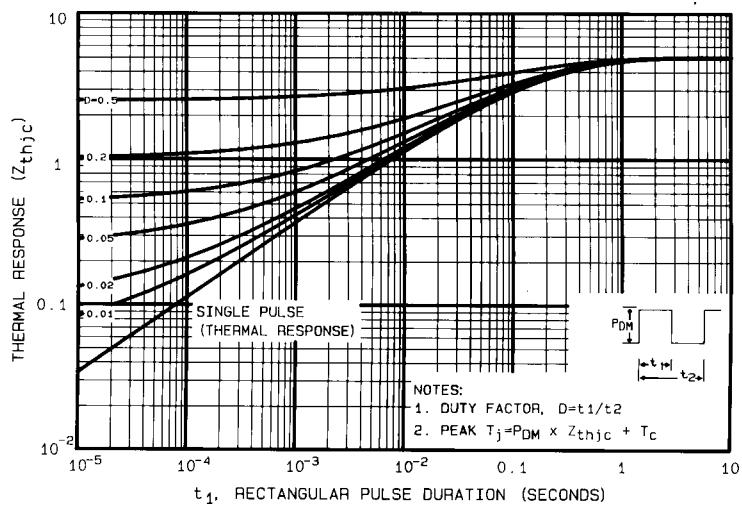


Fig. 11 — Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

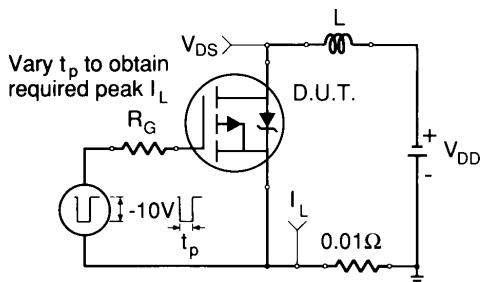


Fig. 12a — Unclamped Inductive Test Circuit

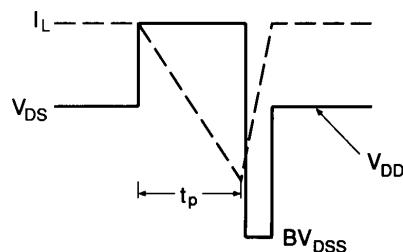


Fig. 12b — Unclamped Inductive Waveforms

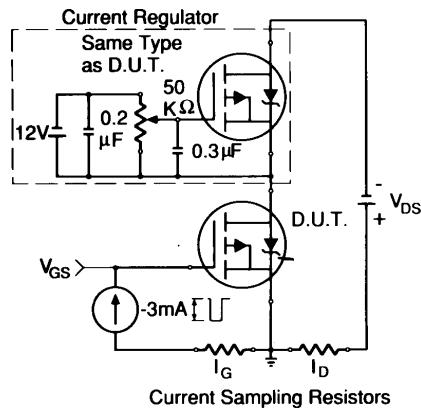


Fig. 13a — Gate Charge Test Circuit

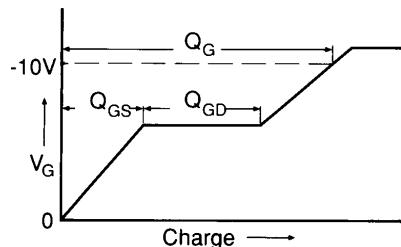
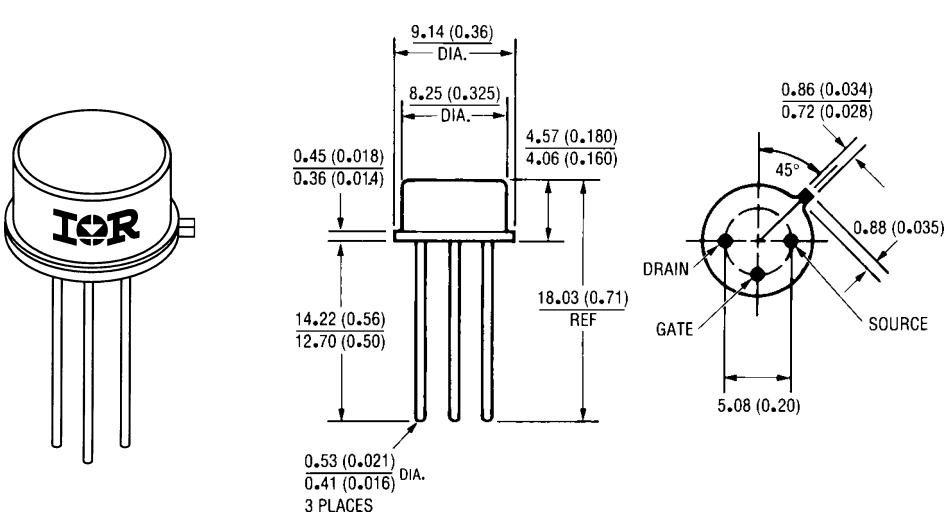


Fig. 13b — Basic Gate Charge Waveform

JANTX2N6849, JANTXV2N6849 Device

- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
(see figure 11)
- ② @ V_{DD} = -25V, Starting T_J = 25°C,
EAS = [0.5 * L * (I_L²) * [BV_{DSS}/(BV_{DSS}-V_{DD})]]
Peak I_L = -6.5A, V_{GS} = -10V, 25 ≤ R_G ≤ 200Ω
- ③ I_{SD} ≤ -6.5A, di/dt ≤ -140A/μs,
V_{DD} ≤ BV_{DSS}, T_J ≤ 150°C
- ④ Pulse width ≤ 300 μs; Duty Cycle ≤ 2%
- ⑤ K/W = °C/W
W/K = W/°C

Case Outline and Dimensions — TO-205AF (Modified TO-39)



All dimensions are shown millimeters (inches)

International
IR Rectifier

WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, Tel: (310) 322 3331

EUROPEAN HEADQUARTERS: Hurst Green, Oxted, Surrey RH8 9BB, UK Tel: ++ 44 1883 732020

IR CANADA: 7321 Victoria Park Ave., Suite 201, Markham, Ontario L3R 2Z8, Tel: (905) 475 1897

IR GERMANY: Saalburgstrasse 157, 61350 Bad Homburg Tel: ++ 49 6172 96590

IR ITALY: Via Liguria 49, 10071 Borgaro, Torino Tel: ++ 39 11 451 0111

IR FAR EAST: K&H Bldg., 2F, 3-30-4 Nishi-Ikeburo 3-Chome, Toshima-Ki, Tokyo Japan 171 Tel: 81 3 3983 0086

IR SOUTHEAST ASIA: 315 Outram Road, #10-02 Tan Boon Liat Building, Singapore 0316 Tel: 65 221 8371